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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Complete if Known

Application Number 09/869,789

Filing Date July 23, 2002

First Named Inventor Hans-Ulrich Krotil et al.

Art Unit 2856

Examiner Name Noland, Thomas

Attorney Docket Number TIL0004

_			U. S. PATENT	DOCUMENTS	
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (7 known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No.1	Foreign Patent Document Country Code* Number * Wind Code* (# known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	τ°
por		EP 0 896 201 A1	02-10-1999	Muramatsu et al.		
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Examiner Signature	ann	J	Date Considered	5/	12/27	

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		Docket Number (Optional)	Application Number
. *	186	TIL0004	09/869,789
· INFO	ORMATION DISCLOSURE PICATION (Use several sheets if necessary)	Applicant(s) Hans-Ulrich Krotil et al.	
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		July 23, 2002	2856
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